

N-Channel Enhancement Mode MOSFET

Description

The HNVTFS5826NLTWG uses advanced trench technology to provide excellent R_{DS(ON)}, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} = 60V I_D =40 A

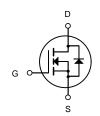
 $R_{DS(ON)}$ < 15m Ω @ V_{GS}=10V

Application

Battery protection

Load switch

Uninterruptible power supply



DFN3X3-8L

N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
HNVTFS5826NLTWG	DFN3X3-8L	HXY MOSFET	5000

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Symbol	Parameter	Parameter Rating	
VDS	Drain-Source Voltage	60	V
VGS	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	40	Α
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	20	Α
IDM	Pulsed Drain Current ²	150	Α
EAS	Single Pulse Avalanche Energy ³	36	mJ
P _D @T _C =25°C	Total Power Dissipation⁴	30	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R _θ JA	Thermal Resistance Junction-ambient ¹	62	°C/W
R₀JC	Thermal Resistance Junction-Case ¹	2.5	°C/W

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Electrical Characteristics (TJ=25℃ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	cteristic					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250µA	60	_	_	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} =0V,	-	-	1.0	μA
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA
On Charac	cteristics					
$V_{GS(th)}$	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250µA	1.0	1.6	2.5	V
Б	Static Drain-Source on-Resistance	V _{GS} =10V, I _D =20A	-	12	15	0
$R_{DS(on)}$		V _{GS} =4.5V, I _D =10A	-	15	20	mΩ
Dynamic (Characteristics					
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	-	930	-	pF
Coss	Output Capacitance		-	230	_	pF
C_{rss}	Reverse Transfer Capacitance		-	8	_	pF
Qg	Total Gate Charge	V _{DS} =30V, I _D =20A, V _{GS} =10V	-	22	-	nC
Q _{gs}	Gate-Source Charge		-	4.5	-	nC
Q_gd	Gate-Drain("Miller") Charge	VGS-10V	-	3.5	-	nC
Switching	Characteristics					
t _{d(on)}	Turn-on Delay Time		-	4.5	-	ns
t _r	Turn-on Rise Time	V _{DD} =30V, I _D =20A,	-	2.7	-	ns
$t_{d(off)}$	Turn-off Delay Time	R_G =1.6 Ω , V_{GS} =10 V	-	13.8	_	ns
t _f	Turn-off Fall Time		-	2.7	-	ns
Drain-Sou	rce Diode Characteristics and Maxim	um Ratings				
Is	Maximum Continuous Drain to Source Diode Forward		_	_	40	Α
	Current					, ,
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	150	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S =30A	-	-	1.2	V
t _{rr}	Body Diode Reverse Recovery Time	T -05°0	-	18	-	ns
Qrr	Body Diode Reverse Recovery Charge	T _J =25℃, I _F =20A,dI/dt=100A/μs	-	12	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

^{2.} EAS condition: TJ=25 $^{\circ}\text{C}$, VDD=30V, VG=10V, RG=25 Ω , L=0.5mH, IAS=12A

^{3.} Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%



Typical Performance Characteristics

Figure1: Output Characteristics

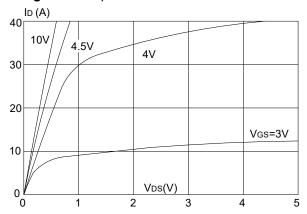


Figure 3:On-resistance vs. Drain Current

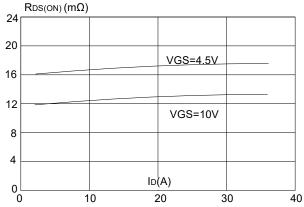


Figure 5: Gate Charge Characteristics

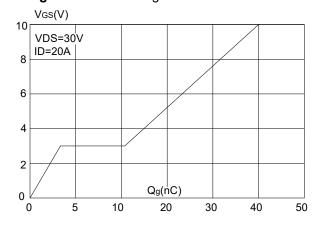


Figure 2: Typical Transfer Characteristics

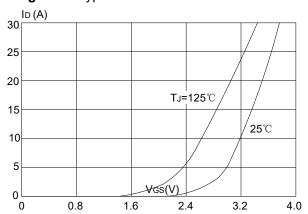


Figure 4: Body Diode Characteristics

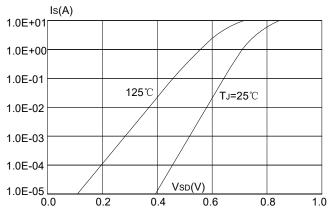
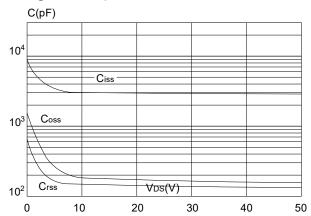


Figure 6: Capacitance Characteristics



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Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

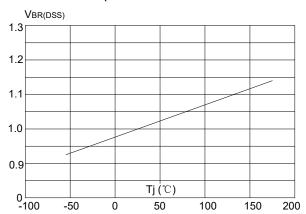


Figure 9: Maximum Safe Operating Area

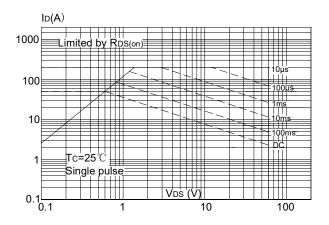


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

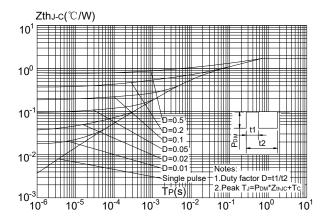


Figure 8: Normalized on Resistance vs. Junction Temperature

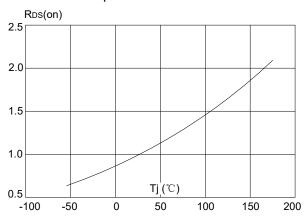
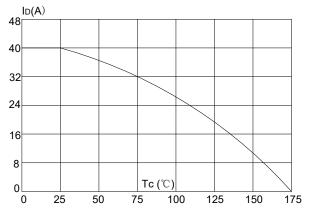
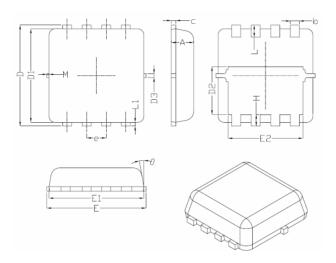


Figure 10: Maximum Continuous Drain Current vs. Case Temperature



DFN3X3-8L Package Information



Symbol	Dimensions In Millimeters			
	Min.	Nom.	Max.	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
С	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.48	1.58	1.68	
D3	-	0.13	-	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
е	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
L1	-	0.13	-	
M	*	*	0.15	
θ		10 [°]	12 [°]	

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